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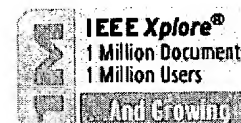
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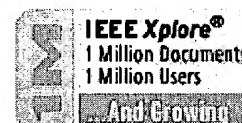
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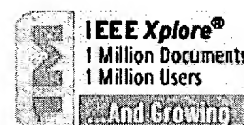
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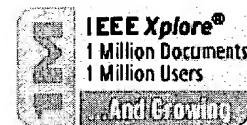
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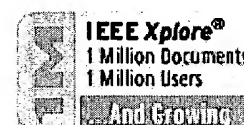
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**1 A thermal-aware superscalar microprocessor***Chee How Lim; Daasch, W.R.; Cai, G.;*

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**1 I have seen the future: it is flooded with email***Reisman, S.;*

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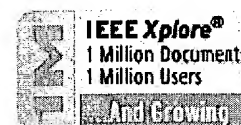
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